

U.S. Department of Commerce, Patent and Trademark		Atty. Docket No.	Application No.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		BTAT.002US1	09/832,933
		Applicant(s)	Conf. No.
(Use several sheets if necessary)		Wu et al.	5253
(Form PTO-1449)		Filing Date	Art Group
		April 11, 2001	2123

U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TS	1	7,003,755	2/2006	Pang et al.			
TS	2	6,209,122	03/2001	Jyu et al.			
TS	3	6,058,496	05/2000	Gillis et al.			
TS	4	6,524,872	02/2003	Cheung			
TS	5	5,600,844	02/1997	Shaw et al.			

U.S. Published Patent Application Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

Foreign Patent Documents

							Translation
		Document	Date	Country	Class	Subclass	Yes

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

TS	6	Kuo, et al., "Simulation of MOSFET Lifetime under AC Hot-Electron Stress," <i>IEEE Transactions on Electron Devices</i> , Vol. 35, No. 7, July, 1988, pp. 1004-1011.
TS	7	Chen, "A Unified Compact Scalable Id Model for Hote Carrier Reliability Simulation," <i>IEEE</i> , March 1999, pp. 243-248.
TS	8	Leblebici et al., "An Integrated Hot-Carrier Degradation Simulator for VLSI Reliability Analysis," <i>Proceeding ICCAD, IEEE</i> , 1990, pp. 400-403.
TS	9	Quader et al., "Hot-Carrier-Reliability Design Rules for Translating Device Degradation to CMOS Digital Circuit Degradation," <i>IEEE Transactions on Electron Devices</i> , Vol. 41, No. 4, May 1994, pp. 681-691.

Examiner	Date Considered	/Thomas Stevens/ (12/04/2006)
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.